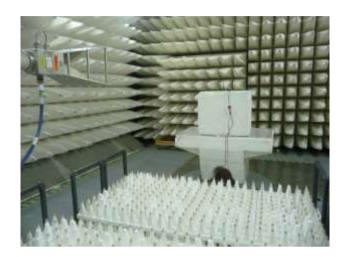
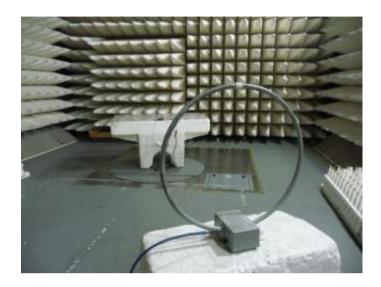
Photograph No.1
Setup for OBW, band edge emission and hopping parameters measurements



Photograph No.2 Setup for spurious field strength measurements in anechoic chamber from 9 kHz to 30 MHz



Photograph No.3
Setup for carrier and spurious emissions measurements in anechoic chamber from 30 MHz to 1 GHz



Photograph No.4 Setup for field strength measurements in anechoic chamber above 1 GHz

